

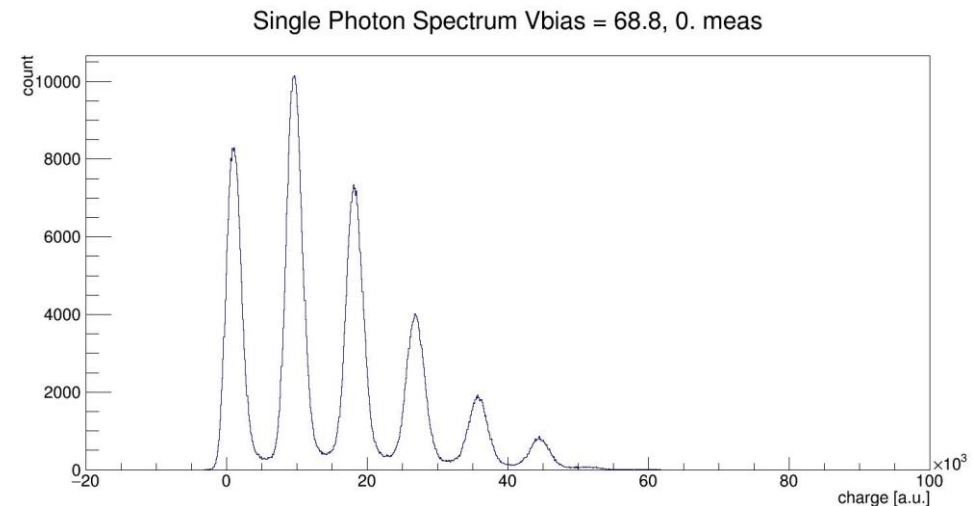
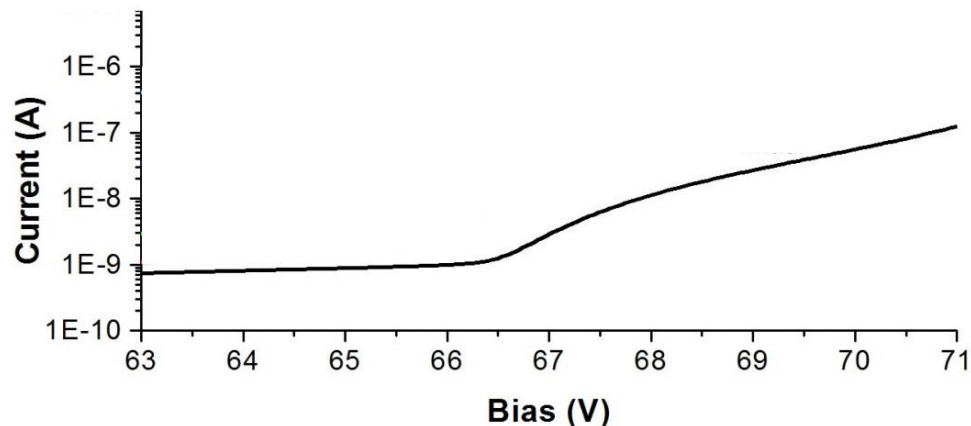
SIPMMEAS-M1.5



Tamas Majoros
Debrecen University

SiPM Characterization

- Goal: select SiPMs with similar response
- Two methods of characterization:
 - SPS measurement (light): gives more information (gain), but slow and does not work with irradiated SiPMs
 - I-V measurement (dark current): fast, simple, gives less information
- SIPMMEAS-M1.5 can be used for both methods

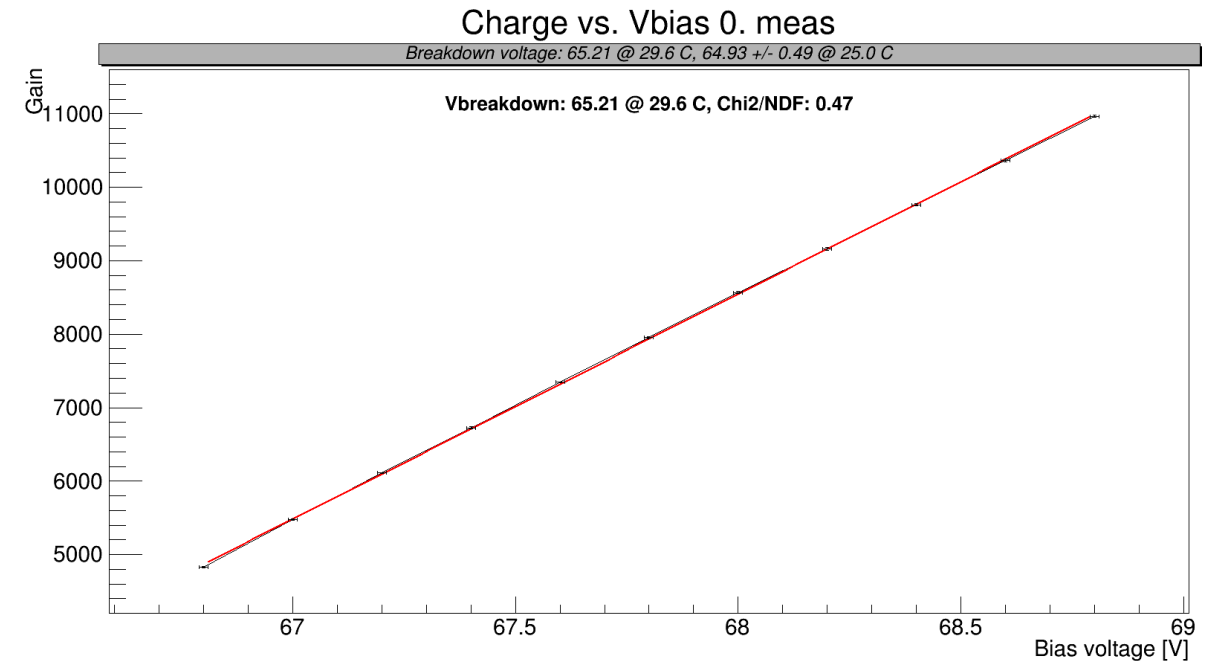
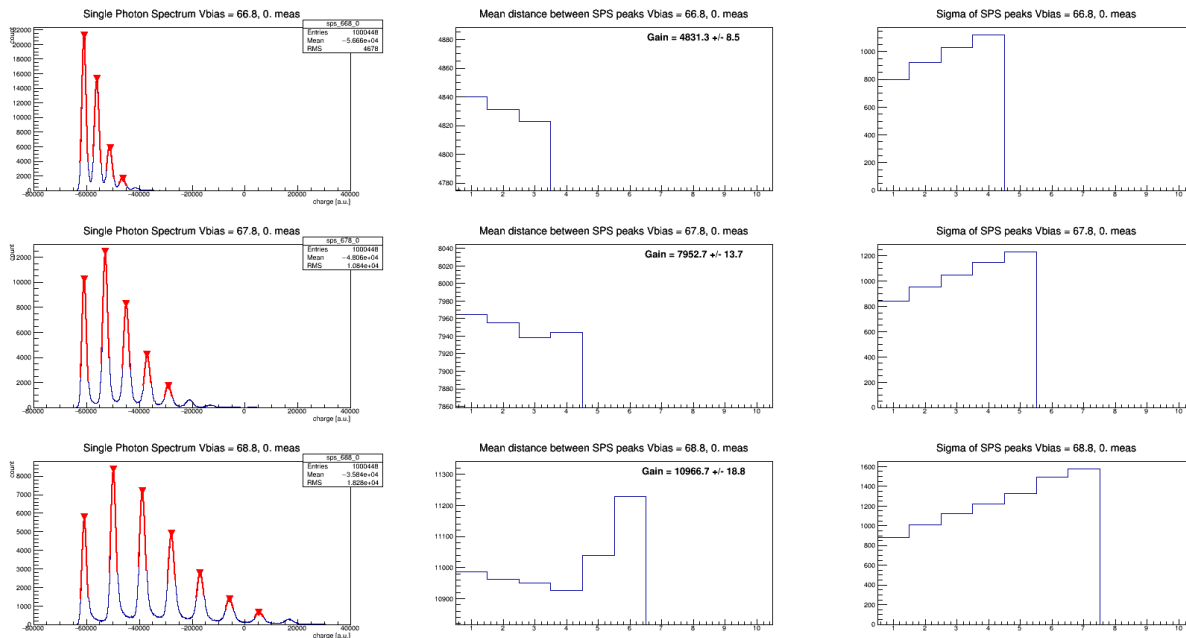


Upgrades from SIPMMEAS-M1

- Replaced analog PCB
- Contains a multiplexer: 4 different SiPMs can be connected to the amplifier
- DC coupled circuit:
 - Able to measure SPS like SIPMMEASM-M1
 - Able to measure I-V curve (new function)
- Modified FPGA code (use LED or not)

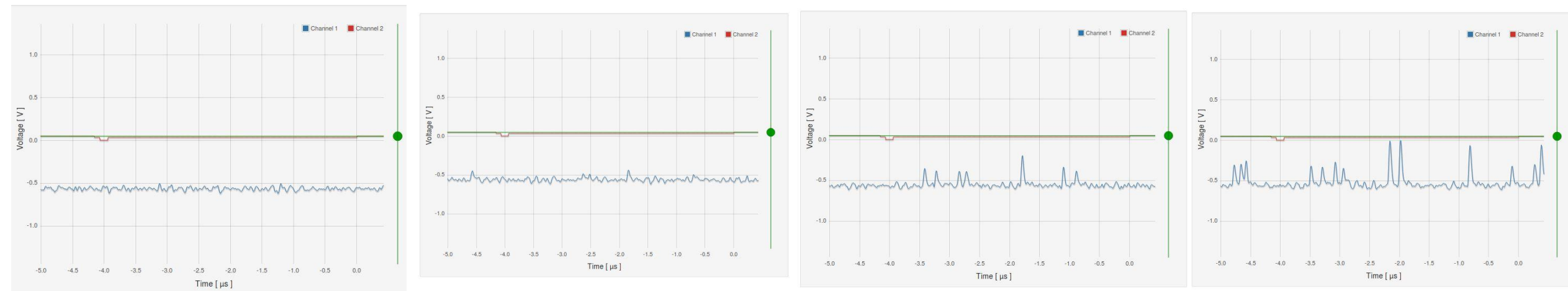
SPS measurement

- Still able to measure SPS spectra and determine breakdown voltage
- Measured V_{BD} is 0.3-0.4 V higher than value given by Hamamatsu (in this example: 64.93 V vs. 64.57 V), we need to find out why



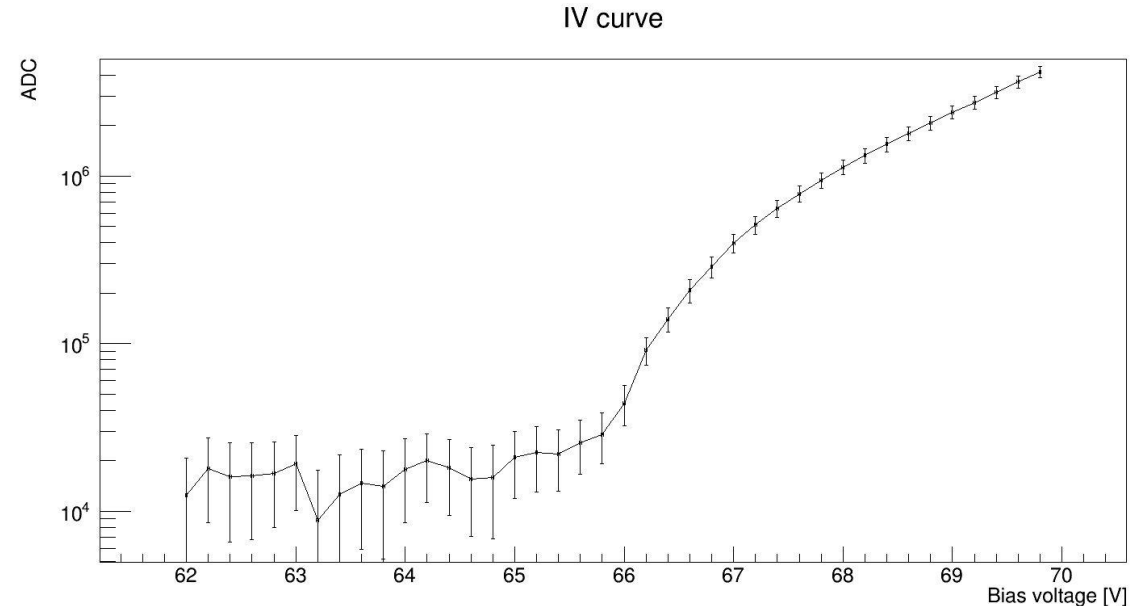
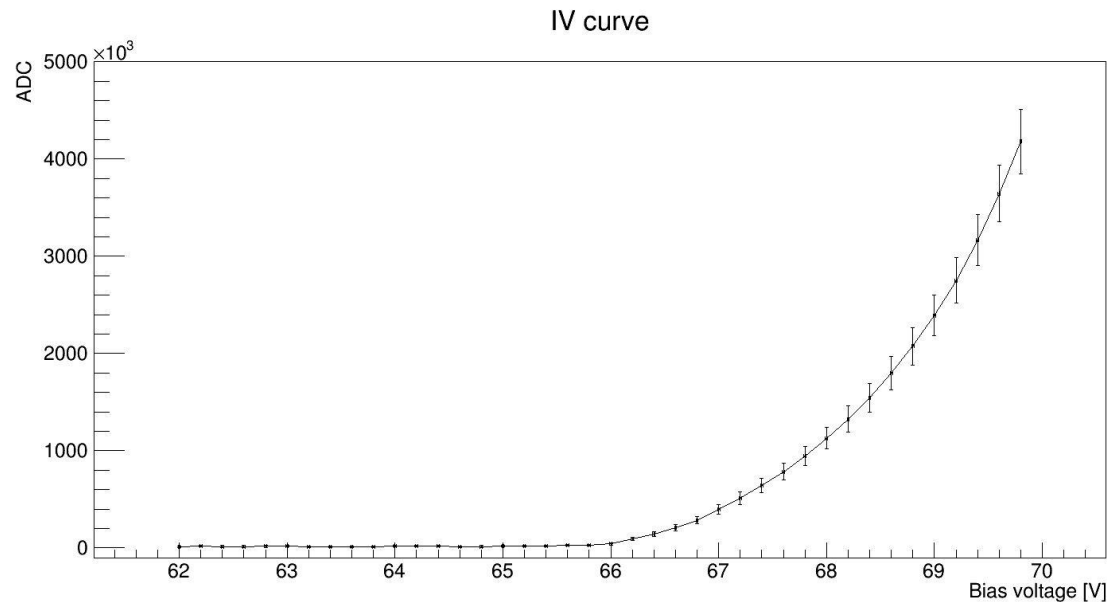
I-V measurement

- LED turned off
- DSP-based dark current measuring: integrating signals in a big integration window
- Oscilloscope figures: 62.6 V, 66.8 V, 68.0 V, 69.2 V



I-V measurement

- New client side data processing application for I-V measurement
- Able to measure the I-V curve
- Will be able to determine breakdown voltage with different methods (work in progress...)



I-V measurement

- Maybe DSP-based current measurement will not be accurate enough, but if we find correlations between real and measured values, measuring and determining the V_{bd} will be possible at any time when the detector is off without any extra hardware
- Next version (SIPMMEAS-M2) will contain a real micro amp meter